Substitute	stitute for form 1449/PTO		Complete if Known			
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	TEMENT BY A			First Named Inventor	TORII, KATSUYUKI	
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	(Use as many sheets as	necessary)		Examiner Name	Alexander Belousov	
Sheet	1	of	1	Attorney Docket Number	082416-001500US	

			U.S. PATENT DO		
Examiner Initials*	Cite No.1	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	AA	Number Kind Code ^{2 (Finose)} US-6.140.184	10-13-2000	Dupuy et al.	
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		NON PATENT LITERATURE DOCUMENTS	
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	AD	Supplementary European Search Report mailed on June 10, 2010 for European Patent Application No. EP 06712632, 11 pages.	
	AE	SZE, S.M., "Semiconductor Devices Physics and Technology", John Wiley & Sons, USA, 1985, pp. 210-212.	

Examiner Signature	Date Considered	

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